

3N90-FC

Power MOSFET

3.0A, 900V N-CHANNEL POWER MOSFET

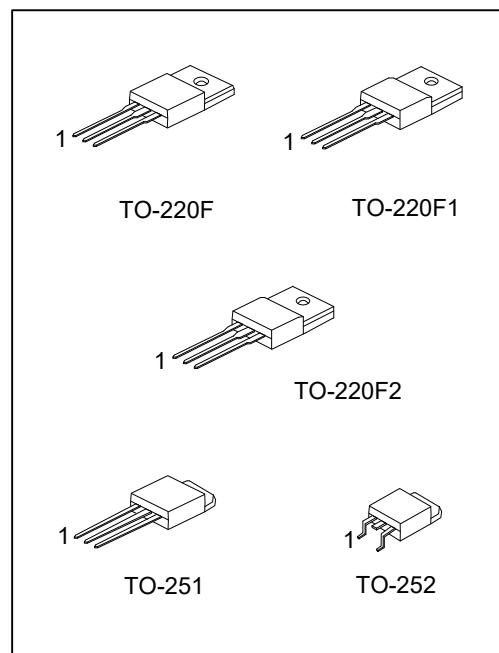
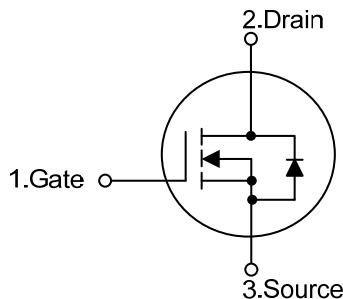
■ DESCRIPTION

The UTC **3N90-FC** provide excellent $R_{DS(ON)}$, low gate charge and operation with low gate voltages. This device is suitable for use as a load switch or in PWM applications.

■ FEATURES

- * $R_{DS(ON)} \leq 6.7 \Omega$ @ $V_{GS}=10V$, $I_D=1.5A$
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

■ SYMBOL



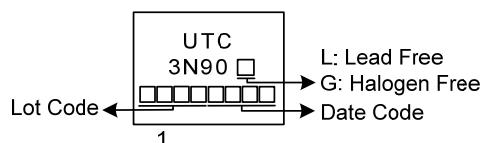
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
3N90L-TF1-T	3N90G-TF1-T	TO-220F1	G	D	S	Tube
3N90L-TF2-T	3N90G-TF2-T	TO-220F2	G	D	S	Tube
3N90L-TF3-T	3N90G-TF3-T	TO-220F	G	D	S	Tube
3N90L-TM3-T	3N90G-TM3-T	TO-251	G	D	S	Tube
3N90L-TN3-R	3N90G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

	(1) T: Tube, R: Tape Reel (2) TF3: TO-220F, TF1: TO-220F1, TF2: TO-220F2 TM3: TO-251, TN3: TO-252 (3) G: Halogen Free and Lead Free, L: Lead Free
--	--

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	900	V
Gate-Source Voltage		V_{GSS}	± 30	V
Continuous Drain Current		I_D	3	A
Pulsed Drain Current (Note 2)		I_{DM}	6	A
Avalanche Energy (Note 3)	Single Pulsed	E_{AS}	109	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.1	V/ns
Power Dissipation ($T_A=25^\circ\text{C}$)	TO-220F/TO-220F1	P_D	25	W
	TO-220F2		44	W
	TO-251/TO-252			
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.
 Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
 3. $L=30\text{mH}$, $I_{AS}=2.7\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^\circ\text{C}$
 4. $I_{SD} \leq 3.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient	TO-220F/TO-220F1	θ_{JA}	62.5	$^\circ\text{C/W}$
	TO-220F2		110	$^\circ\text{C/W}$
	TO-251/TO-252			
Junction to Case	TO-220F/TO-220F1	θ_{JC}	5	$^\circ\text{C/W}$
	TO-220F2			
	TO-251/TO-252		2.84 (Note)	$^\circ\text{C/W}$

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

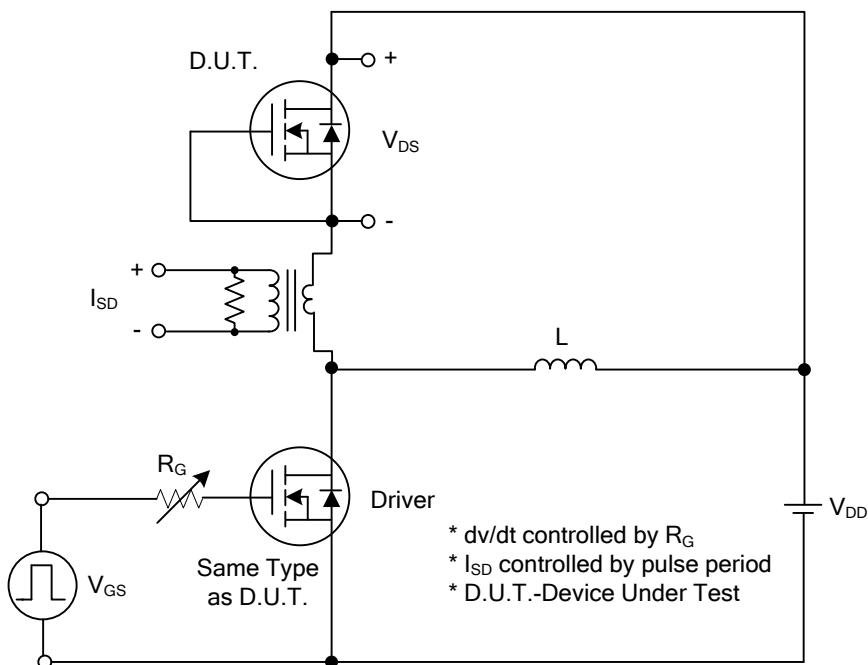
■ ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_{\text{D}} = 250\mu\text{A}$	900			V
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}} = 900\text{V}, V_{\text{GS}} = 0\text{V}$		10		μA
Gate-Source Leakage Current	Forward	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
	Reverse	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{\text{GS}(\text{TH})}$	$V_{\text{DS}} = V_{\text{GS}}, I_{\text{D}} = 250\mu\text{A}$	3.0		5.0	V
Static Drain-Source On-State Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_{\text{D}} = 1.5\text{A}$			6.7	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{ISS}	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$		401		pF
Output Capacitance	C_{OSS}			44		pF
Reverse Transfer Capacitance	C_{RSS}			2.2		pF
SWITCHING CHARACTERISTICS						
Total Gate Charge	Q_G	$V_{\text{DS}} = 720\text{V}, V_{\text{GS}} = 10\text{V}, I_{\text{D}} = 3\text{A}, I_{\text{G}} = 1\text{mA}$ (Note 1, 2)		14.6		nC
Gate-Source Charge	Q_{GS}			7.3		nC
Gate-Drain Charge	Q_{GD}			1.8		nC
Turn-On Delay Time	$t_{\text{D}(\text{ON})}$			7		ns
Turn-On Rise Time	t_R			14.2		ns
Turn-Off Delay Time	$t_{\text{D}(\text{OFF})}$			13.6		ns
Turn-Off Fall Time	t_F			25.2		ns
DRAIN-SOURCE DIODE CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I_S				3	A
Continuous Drain-Source Current	I_{SD}				6	A
Drain-Source Diode Forward Voltage	V_{SD}	$I_S = 3\text{A}, V_{\text{GS}} = 0\text{V}$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 3\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		390		ns
Reverse Recovery Charge	Q_{rr}			2.8		μC

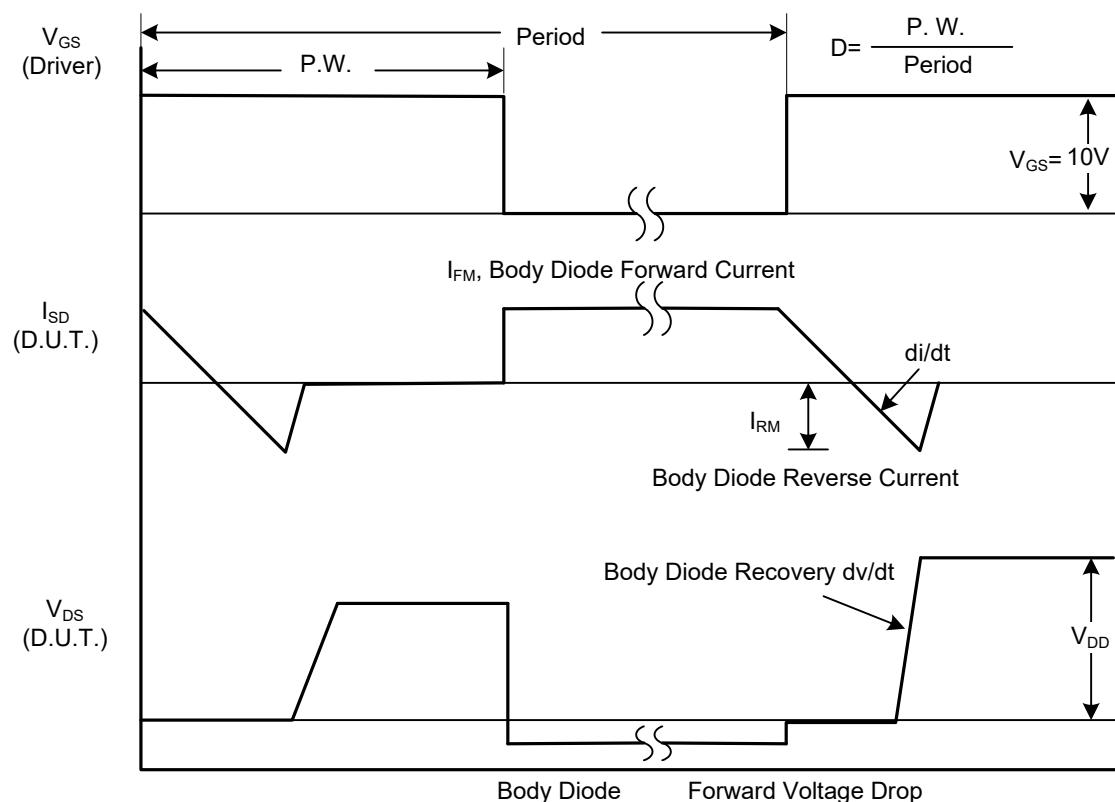
Notes: 1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

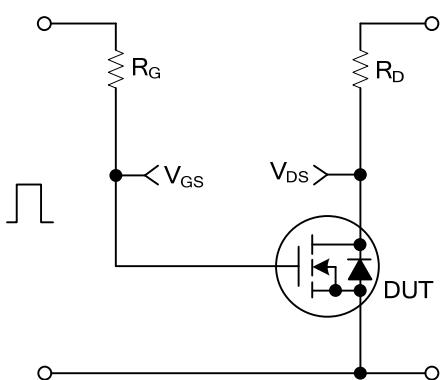


Peak Diode Recovery dv/dt Test Circuit

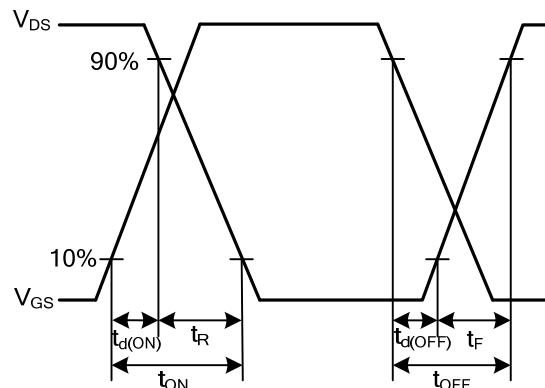


Peak Diode Recovery dv/dt Waveforms

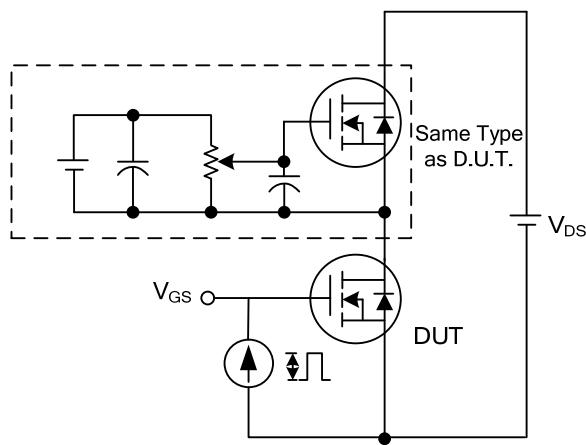
■ TEST CIRCUITS AND WAVEFORMS



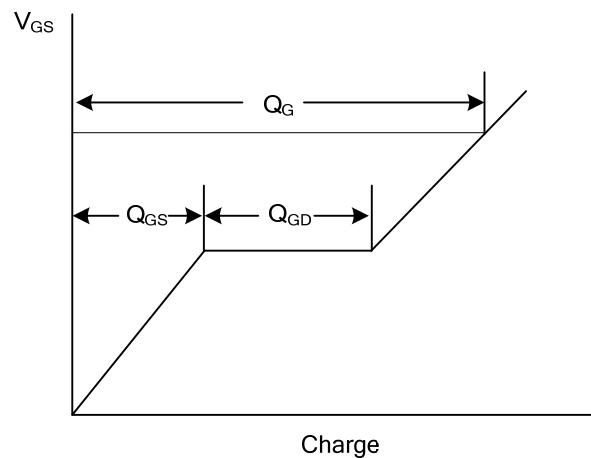
itching Test Circuit



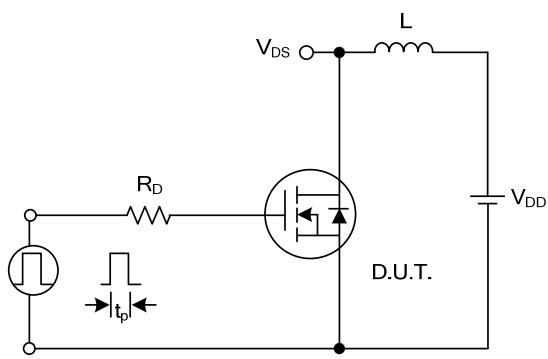
Switching Waveforms



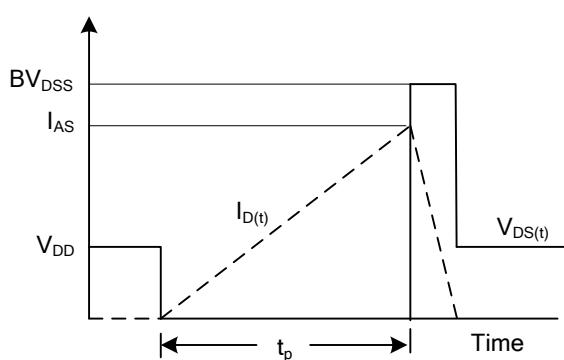
Gate Charge Test Circuit



Gate Charge Waveform

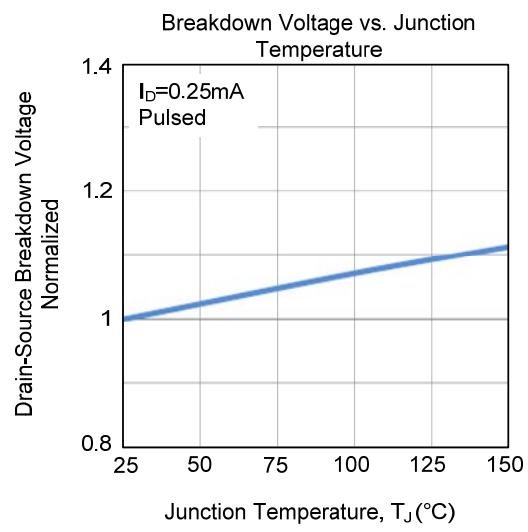
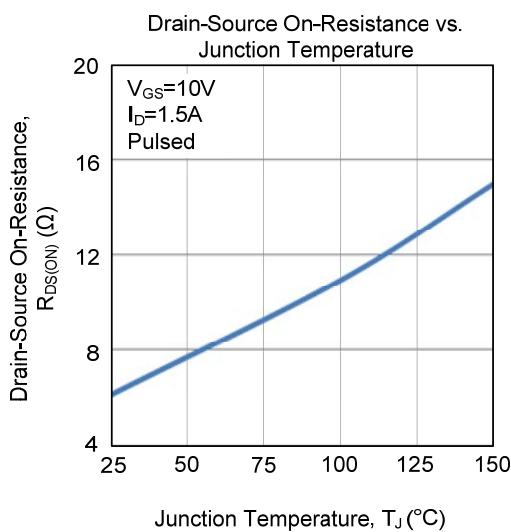
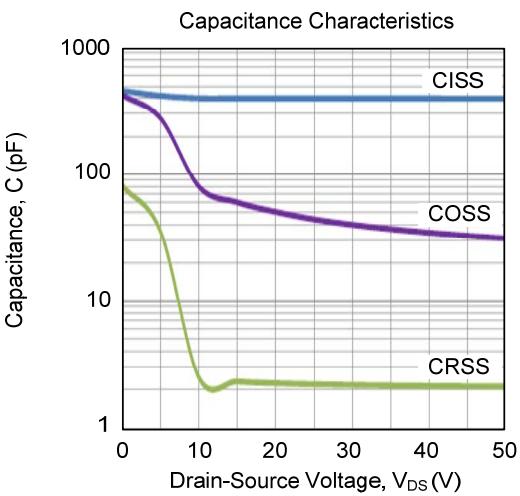
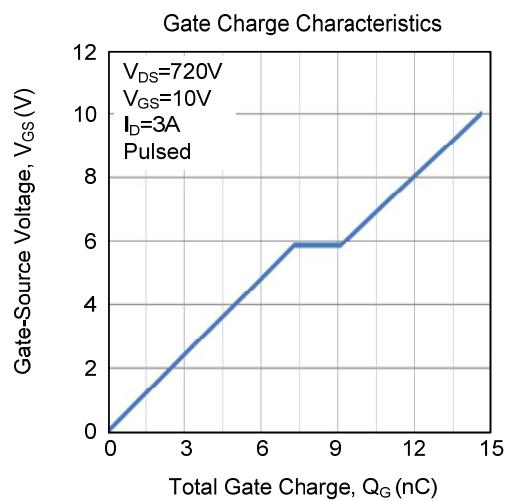
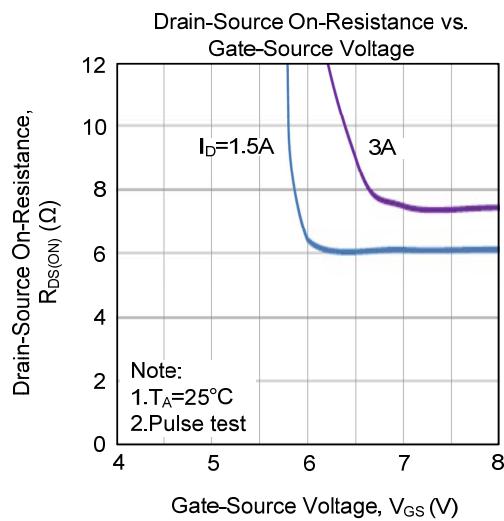
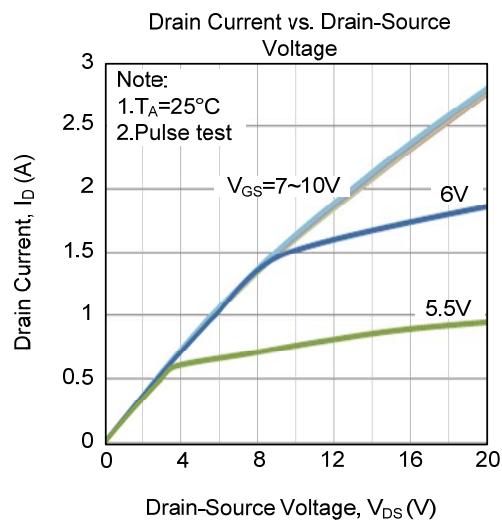


Unclamped Inductive Switching Test Circuit

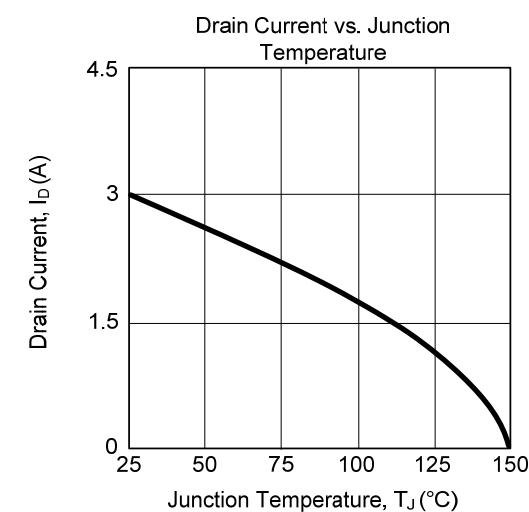
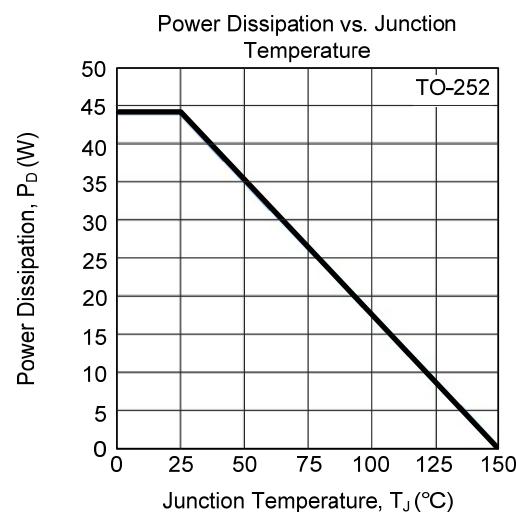
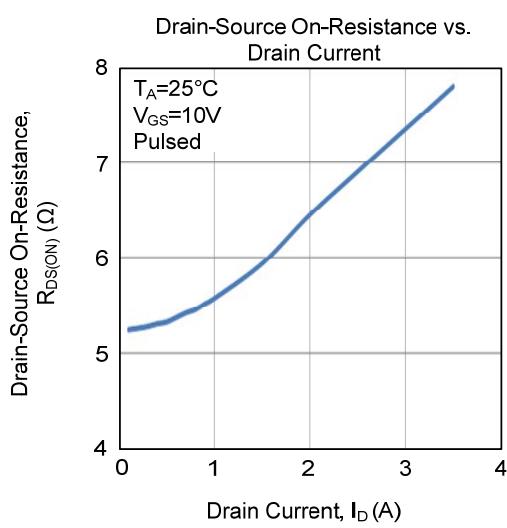
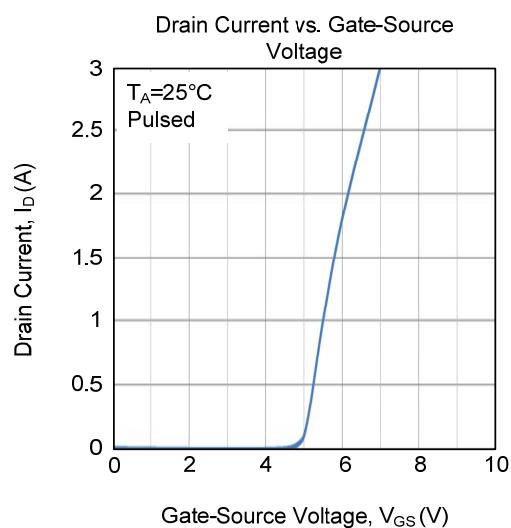
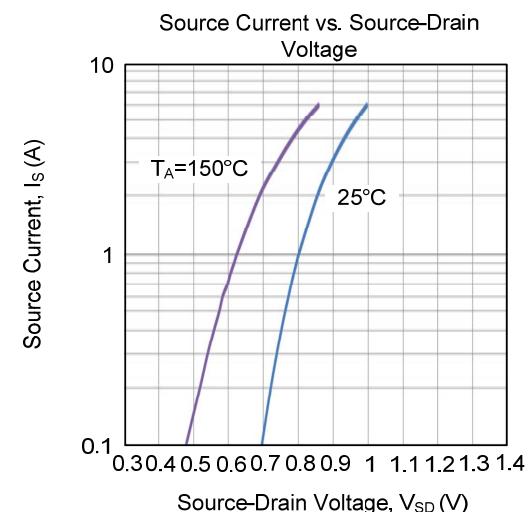
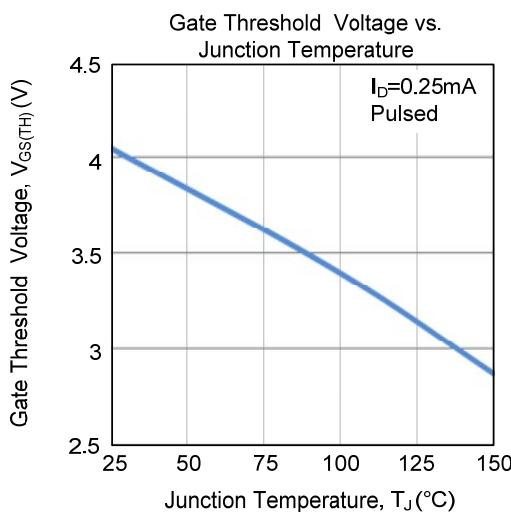


Unclamped Inductive Switching Waveforms

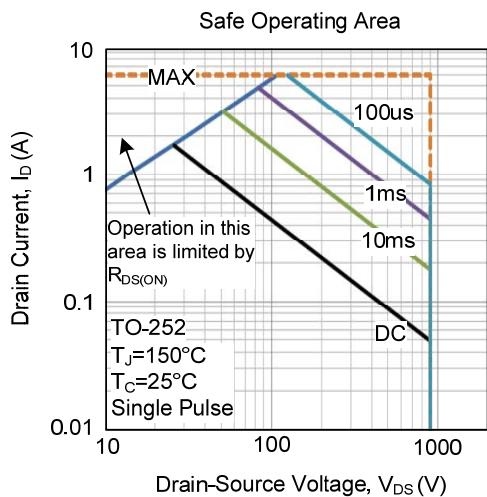
■ TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.